Application/Control No.	Applicant(s)/Patent under Reexamination	
10/038,169	BONEH ET AL.	
Examiner	Art Unit	
Baotran N. To	2135	

	SEAR	CHED	
Class	Subclass	Date	Examiner
713	165, 189	1/4/2007	вт
726	2	1/4/2007	ВТ
705	51	1/4/2007	ВТ
709	223	1/4/2007	ВТ
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INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
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	DATE	EXMR
EAST SEARCH (USPAT; USPGPUB; EPO; JPO; DERWENT; IBM_TDB)	1/4/2007	вт
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